

APT8016DFN 800V 47.0A 0.16 Ω  
 APT7516DFN 750V 47.0A 0.16 Ω

# POWER MOS IV™

## N - CHANNEL ENHANCEMENT MODE HIGH VOLTAGE POWER MOSFETS

### MAXIMUM RATINGS

All Ratings:  $T_C = 25^\circ\text{C}$  unless otherwise specified.

Symbol	Parameter	APT7516DFN	APT8016DFN	UNIT
$V_{DSS}$	Drain-Source Voltage	750	800	Volts
$I_D$	Continuous Drain Current	47		Amps
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	188		Amps
$V_{GS}$	Gate-Source Voltage	±30		Volts
$P_D$	Total Power Dissipation @ $T_C = 25^\circ\text{C}$ , Derate Above $25^\circ\text{C}$	830		Watts
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to 150		°C

### STATIC ELECTRICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$BV_{DSS}$	Drain-Source Breakdown Voltage ( $V_{GS} = 0V, I_D = 250 \mu\text{A}$ )	APT8016DFN	800		Volts
		APT7516DFN	750		Volts
$I_{DSS}$	Zero Gate Voltage Drain Current ( $V_{DS} = V_{DSS}, V_{GS} = 0V$ ) ( $V_{DS} = 0.8 V_{DSS}, V_{GS} = 0V, T_C = 25^\circ\text{C}$ )			250	$\mu\text{A}$
				1000	$\mu\text{A}$
$I_{GSS}$	Gate-Source Leakage Current ( $V_{GS} = \pm 30V, V_{DS} = 0V$ )			±100	nA
$I_D(ON)$	On State Drain Current <sup>2</sup> ( $V_{DS} > I_D(ON) \times R_{DS(ON)}$ Max, $V_{GS} = 10V$ )	47			Amps
$V_{GS(TH)}$	Gate Threshold Voltage ( $V_{DS} = V_{GS}, I_D = 1mA$ )	2		4	Volts
$R_{DS(ON)}$	Static Drain-Source On-State Resistance <sup>2</sup> ( $V_{GS} = 10V, I_D = 0.5 I_D(Cont.)$ )			0.21	Ohms

### THERMAL CHARACTERISTICS

Symbol	Characteristic	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction to Case			0.15	°C/W
$R_{\theta JA}$	Junction to Ambient			20	°C/W
$T_L$	Max. Lead Temp. for Soldering Conditions: 0.063" from Case for 10 Sec.			300	°C

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DYNAMIC CHARACTERISTICS

APT8016/7516DFN

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1\text{ MHz}$		11320	13000	pF
$C_{oss}$	Output Capacitance			1655	2317	pF
$C_{rss}$	Reverse Transfer Capacitance			578	870	pF
$Q_g$	Total Gate Charge <sup>3</sup>	$V_{GS} = 10V, I_D = I_D [\text{Cont.}]$ $V_{DD} = 0.5 V_{DSS}$		445	675	nC
$Q_{gs}$	Gate-Source Charge			49	75	nC
$Q_{gd}$	Gate-Drain ("Miller") Charge			227	340	nC
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 0.5 V_{DSS}$ $I_D = I_D [\text{Cont.}], V_{GS} = 15V$ $R_G = 0.6$		19	38	ns
$t_r$	Rise Time			29	58	ns
$t_{d(off)}$	Turn-off Delay Time			128	190	ns
$t_f$	Fall Time			40	80	ns

T-39-15

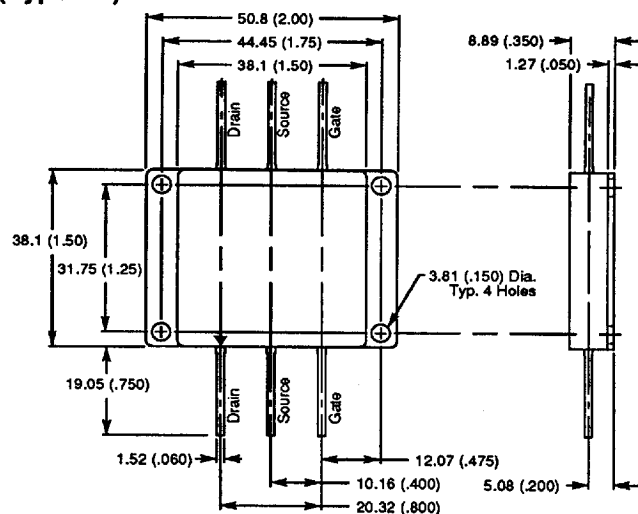
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$I_S$	Continuous Source Current (Body Diode)			47	Amps
$I_{SM}$	Pulsed Source Current <sup>1</sup> (Body Diode)			188	Amps
$V_{SD}$	Diode Forward Voltage <sup>2</sup> ( $V_{GS} = 0V, I_S = -I_D [\text{Cont.}]$ )			1.3	Volts
$t_{rr}$	Reverse Recovery Time ( $I_S = -I_D [\text{Cont.}], di_S/dt = 100A/\mu s$ )	440	880	1700	ns
$Q_{rr}$	Reverse Recovery Charge	12	25	50	$\mu C$

SAFE OPERATING AREA CHARACTERISTICS

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
SOA1	Safe Operating Area	$V_{DS} = 0.4 V_{DSS}, I_{DS} = P_D / 0.4 V_{DSS}, t = 1\text{ Sec.}$	830			Watts
SOA2	Safe Operating Area	$I_{DS} = I_D [\text{Cont.}], V_{DS} = P_D / I_D [\text{Cont.}], t = 1\text{ Sec.}$	830			Watts
$I_{LM}$	Inductive Current Clamped		188			Amps

F-Pack Package Outline (Type DF)



- 1.) Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2.) Pulse Test: Pulse width < 380  $\mu s$   
Duty Cycle < 2%
- 3.) See MIL-STD-750 Method 3471